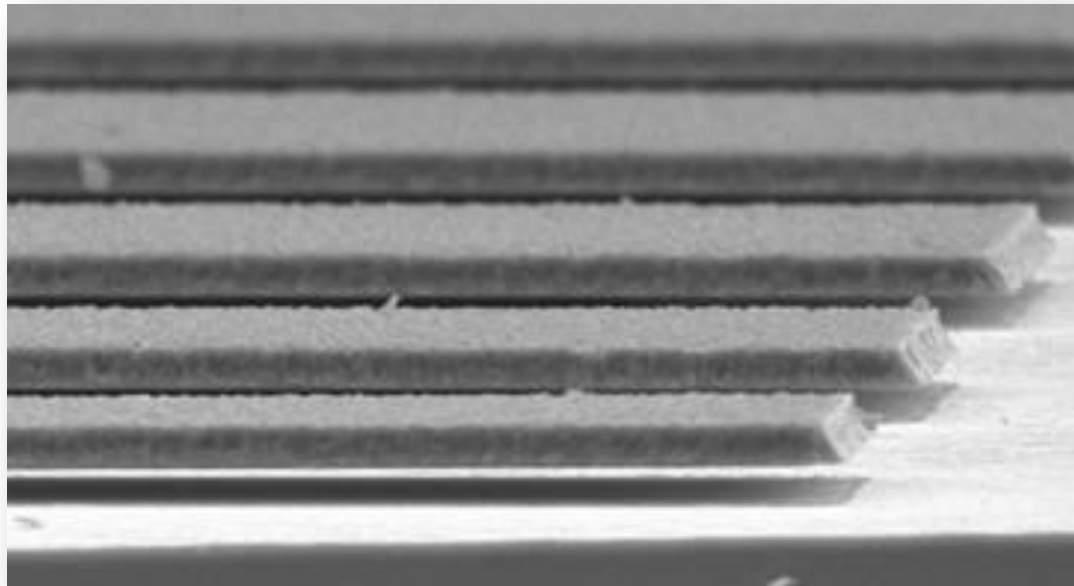


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## A probabilistic multi-scale model for polycrystalline MEMS resonators



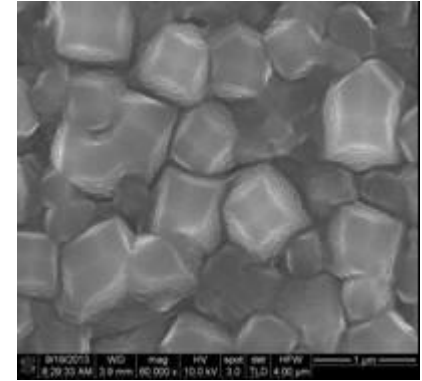
*Lucas Vincent  
Wu Ling  
Paquay Stéphane  
Golinval Jean-Claude  
Noels Ludovic*

3SMVIB: The research has been funded by the Walloon Region under the agreement no 1117477 (CT-INT 2011-11-14) in the context of the ERA-NET MNT framework.

# The problem

- MEMS structures

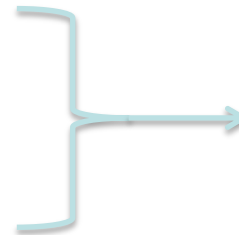
- Are not several orders larger than their micro-structure size
- As a result, their macroscopic properties can exhibit a **scatter**
  - Due to the fabrication process
  - Due to uncertainties of the material
  - ...



➔ The objective of this work is to estimate this scatter

- Up to now, the only sources of uncertainty is due to the material

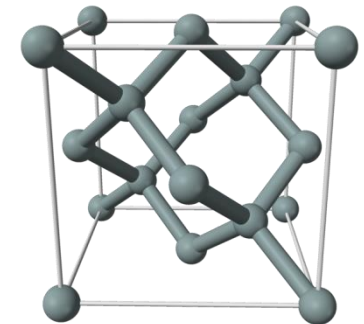
- Silicon crystals are anisotropic
- Polysilicon is polycrystalline



Each grain has a random orientation

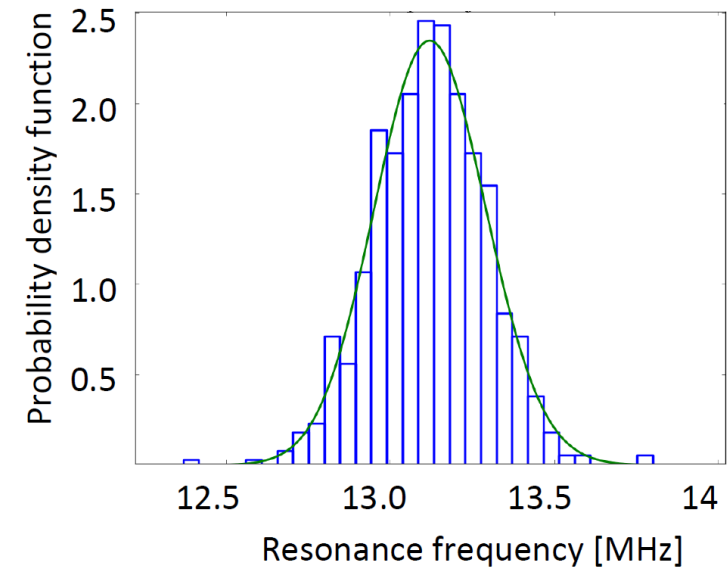
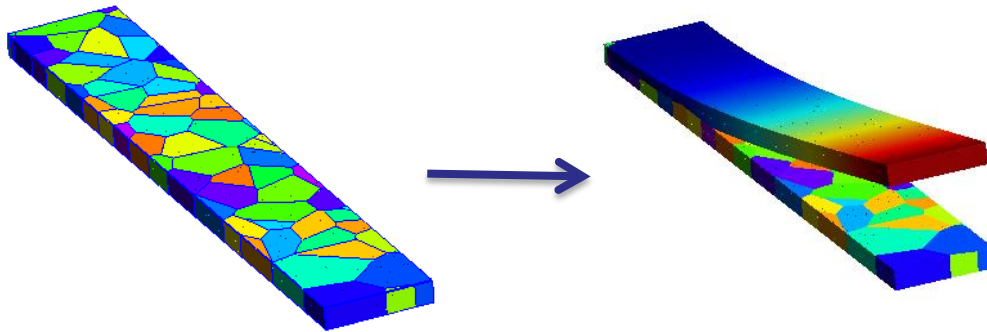
- Characteristics of our model:

- Clamped microbeam
- Macroscopic property of interest: first mode eigenfrequency
  - For a MEMS gyroscope for example



# Monte-Carlo for a fully modelled beam

- The first mode frequency distribution can be obtained with
  - A 3D beam with each grain modelled
  - and a Monte-Carlo simulation of this model

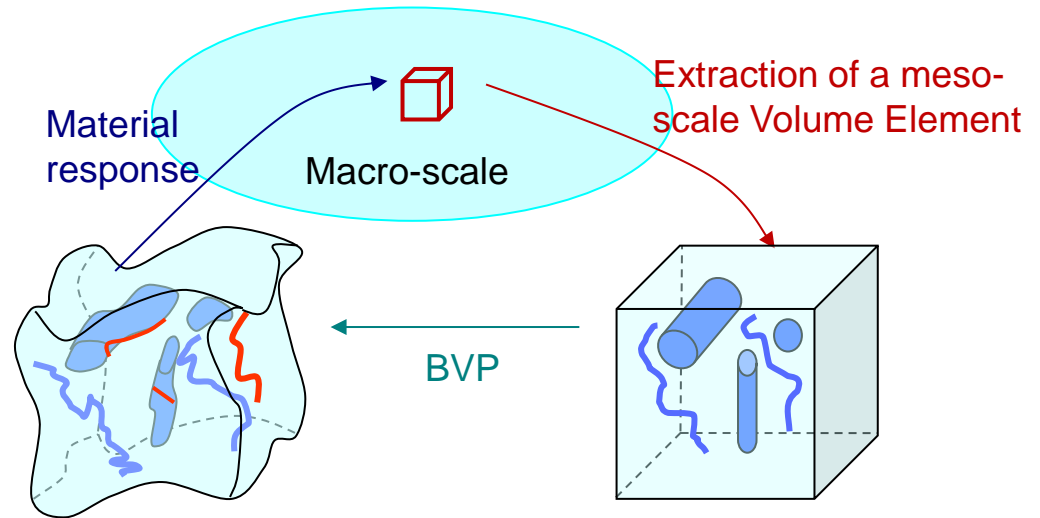


- Considering each grain is expensive and time consuming

↳ Motivation for stochastic multi-scale methods

- Multi-scale modelling

- 2 problems are solved concurrently
  - The macro-scale problem
  - The meso-scale problem (on a meso-scale Volume Element)



- Length-scales separation

$$L_{\text{macro}} \gg L_{\text{VE}} \gg L_{\text{micro}}$$

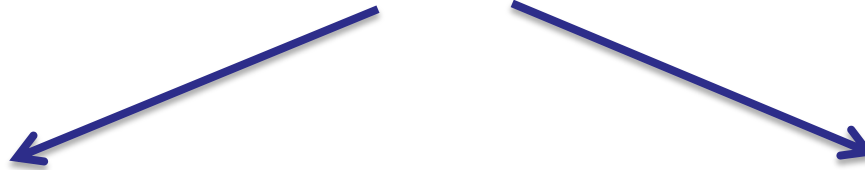
For accuracy: Size of the meso-scale volume element smaller than the characteristic length of the macro-scale loading

To be statistically representative: Size of the meso-scale volume element larger than the characteristic length of the micro-structure

# Motivations

- For structures not several orders larger than the micro-structure size

$$L_{\text{macro}} \gg L_{\text{VE}} \sim L_{\text{micro}}$$



For accuracy: Size of the meso-scale volume element smaller than the characteristic length of the macro-scale loading

Meso-scale volume element no longer statistically representative: Stochastic Volume Elements\*

- Possibility to propagate the uncertainties from the micro-scale to the macro-scale

\*M Ostoja-Starzewski, X Wang, 1999

P Trovalusci, M Ostoja-Starzewski, M L De Bellis, A Murralli, 2015

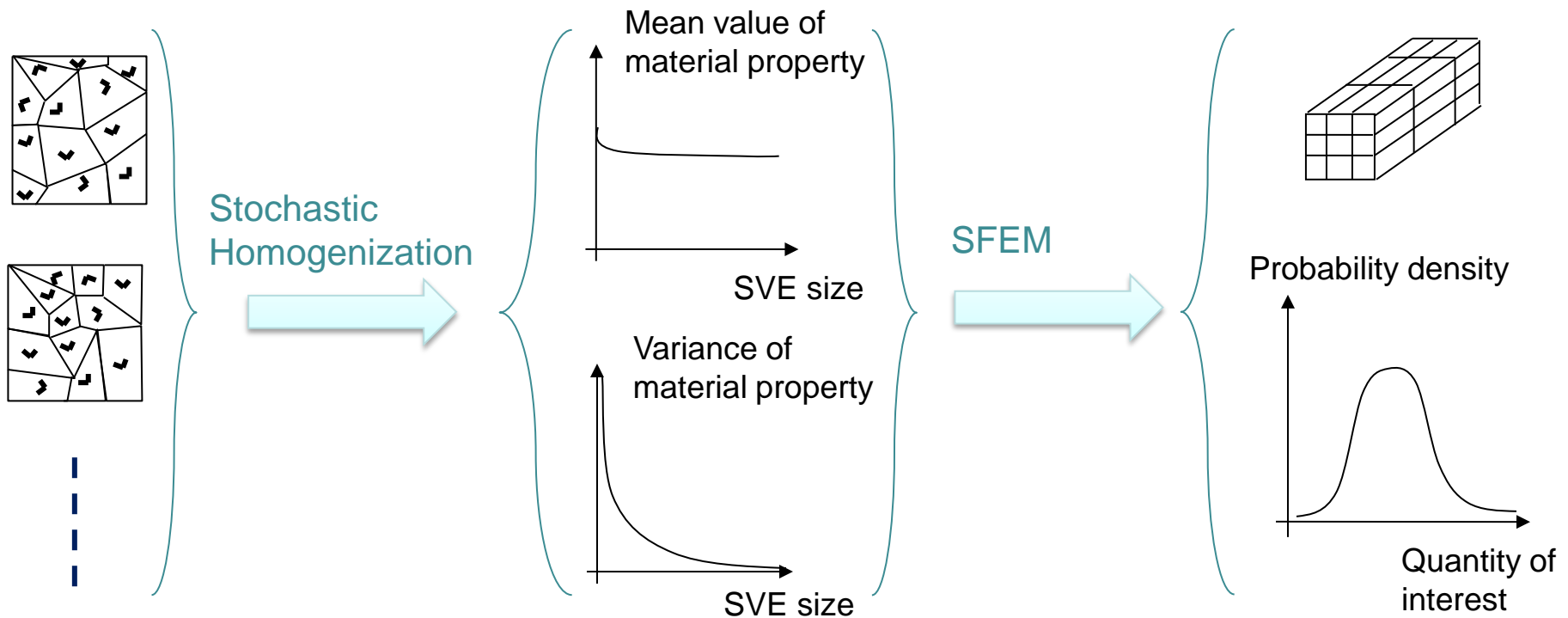
X. Yin, W. Chen, A. To, C. McVeigh, 2008

J. Guilleminot, A. Noshadravan, C. Soize, R. Ghanem, 2011

....

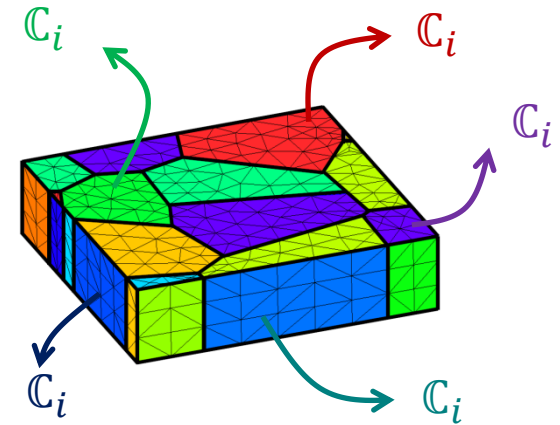
# A 3-scale procedure

Grain-scale or micro-scale	Meso-scale	Macro-scale
<ul style="list-style-type: none"> <li>➤ Samples of the microstructure (volume elements) are generated</li> <li>➤ Each grain has a random orientation</li> </ul>	<ul style="list-style-type: none"> <li>➤ Intermediate scale</li> <li>➤ The distribution of the material property <math>\mathbb{P}(C)</math> is defined</li> </ul>	<ul style="list-style-type: none"> <li>➤ Uncertainty quantification of the macro-scale quantity</li> <li>➤ E.g. the first mode frequency <math>\mathbb{P}(f_1)</math></li> </ul>



- Definition of Stochastic Volume Elements (SVEs)

- Poisson Voronoï tessellation
- Each grain  $i$  is assigned an elasticity tensor  $\mathbb{C}_i$
- $\mathbb{C}_i$  defined from silicon crystal properties
- Each  $\mathbb{C}_i$  is assigned a random rotation
- Mixed BCs



- Stochastic homogenization

- Several realizations

$$\sigma_{m^i} = \mathbb{C}_i : \epsilon_{m^i} \quad , \forall i$$



Computational  
homogenization

$$\sigma_M = \mathbb{C}_M : \epsilon_M$$

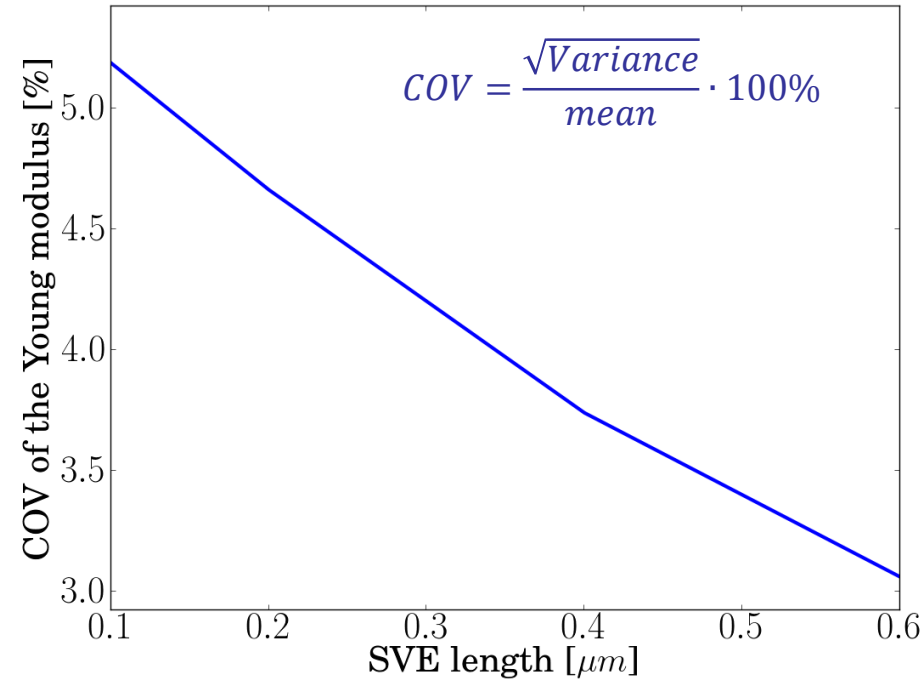
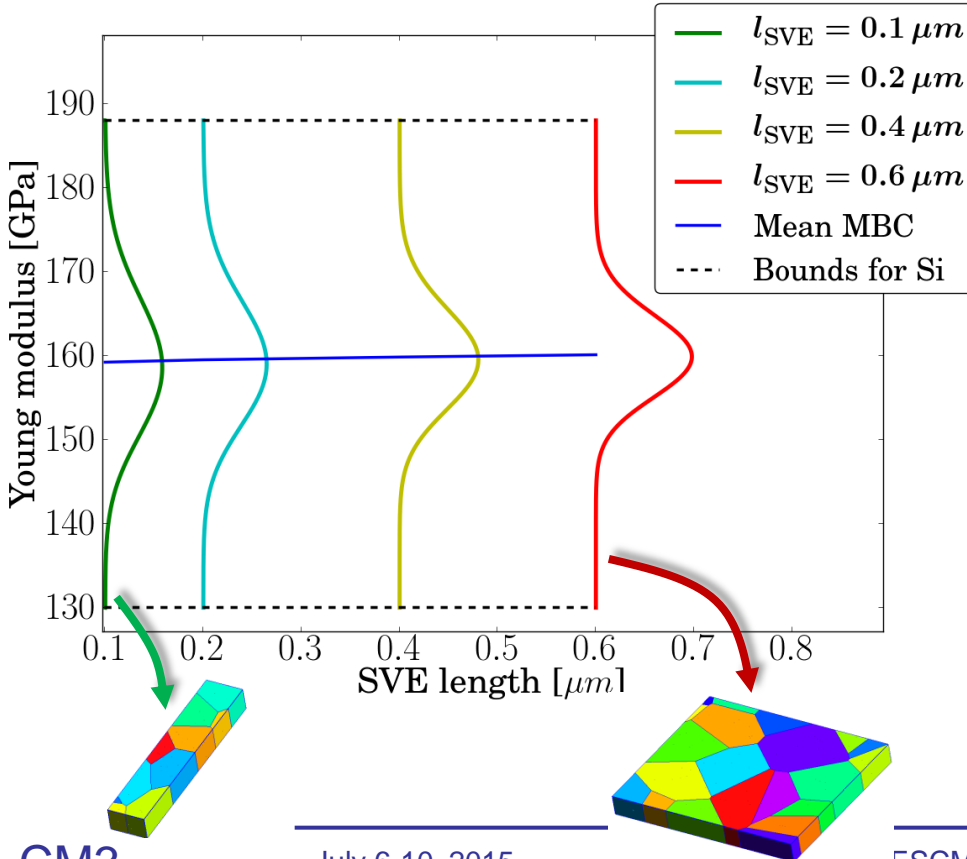
Samples of the meso-scale homogenized elasticity tensors

- Homogenized elasticity tensor not unique as statistical representativeness is lost\*
  - It is thus called apparent elasticity tensor

\*C. Huet, 1990

# From the micro-scale to the meso-scale

- Distribution of the apparent meso-scale elasticity tensor  $\mathbb{C}_M$ 
  - For large SVEs, the apparent tensor tends to the effective (and unique) one

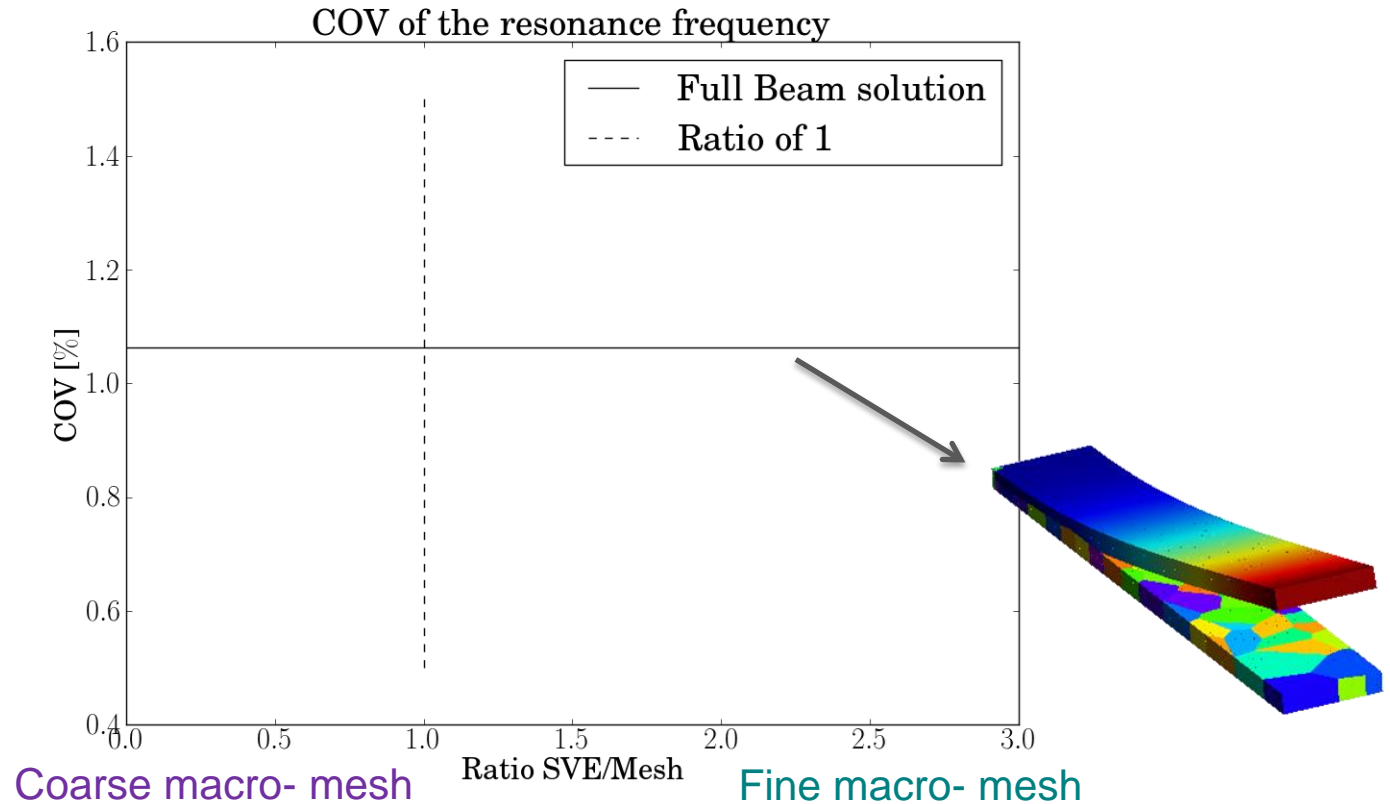
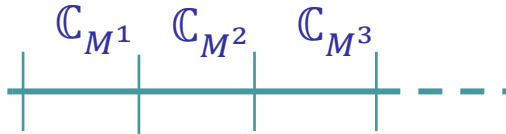


- The bounds do not depend on the SVE size but on the silicon elasticity tensor
- However, the larger the SVE, the lower the probability to be close to the bounds



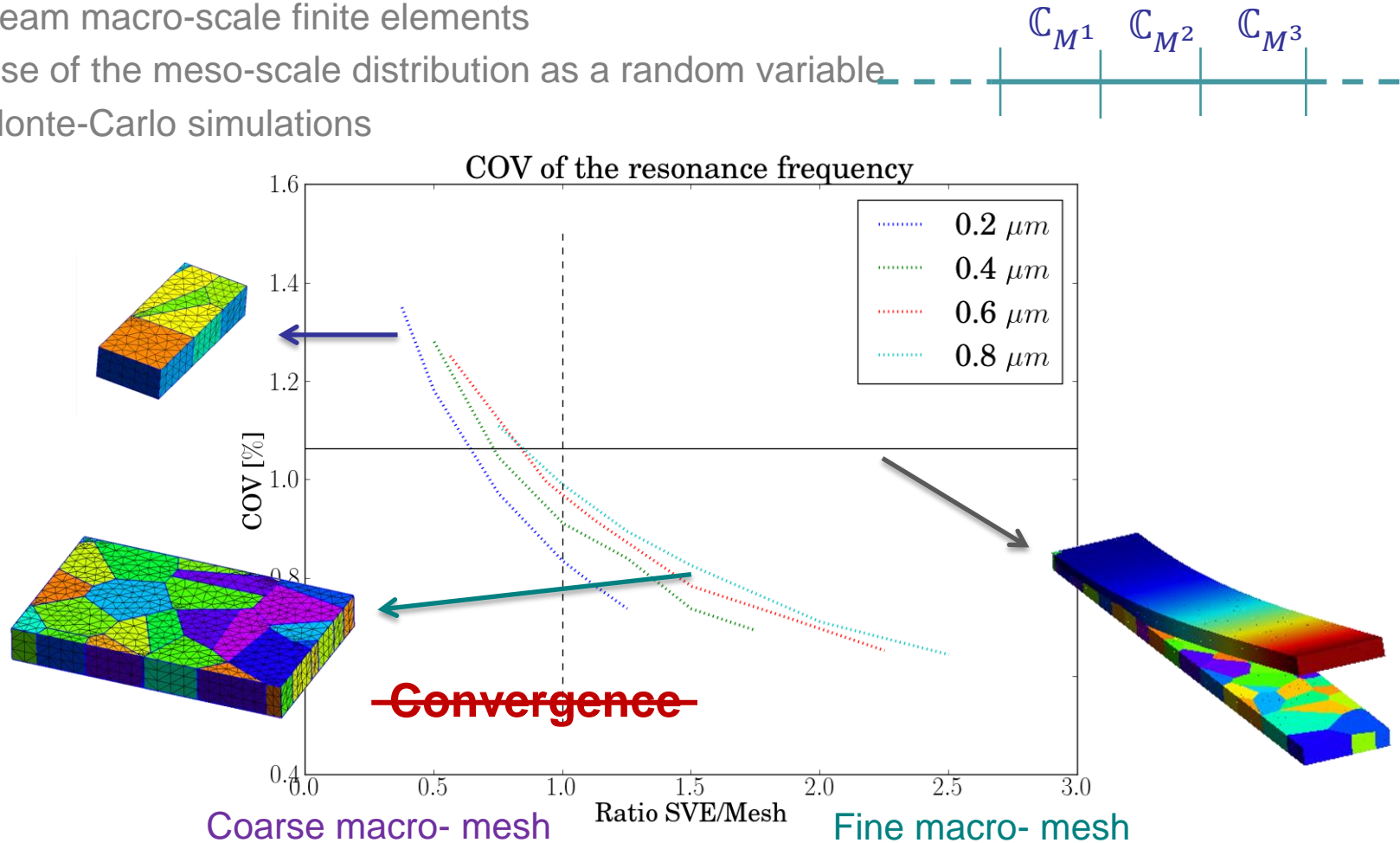
# From the micro-scale to the meso-scale

- Use of the meso-scale distribution with macro-scale finite elements
  - Beam macro-scale finite elements
  - Use of the meso-scale distribution as a random variable
  - Monte-Carlo simulations



# From the micro-scale to the meso-scale

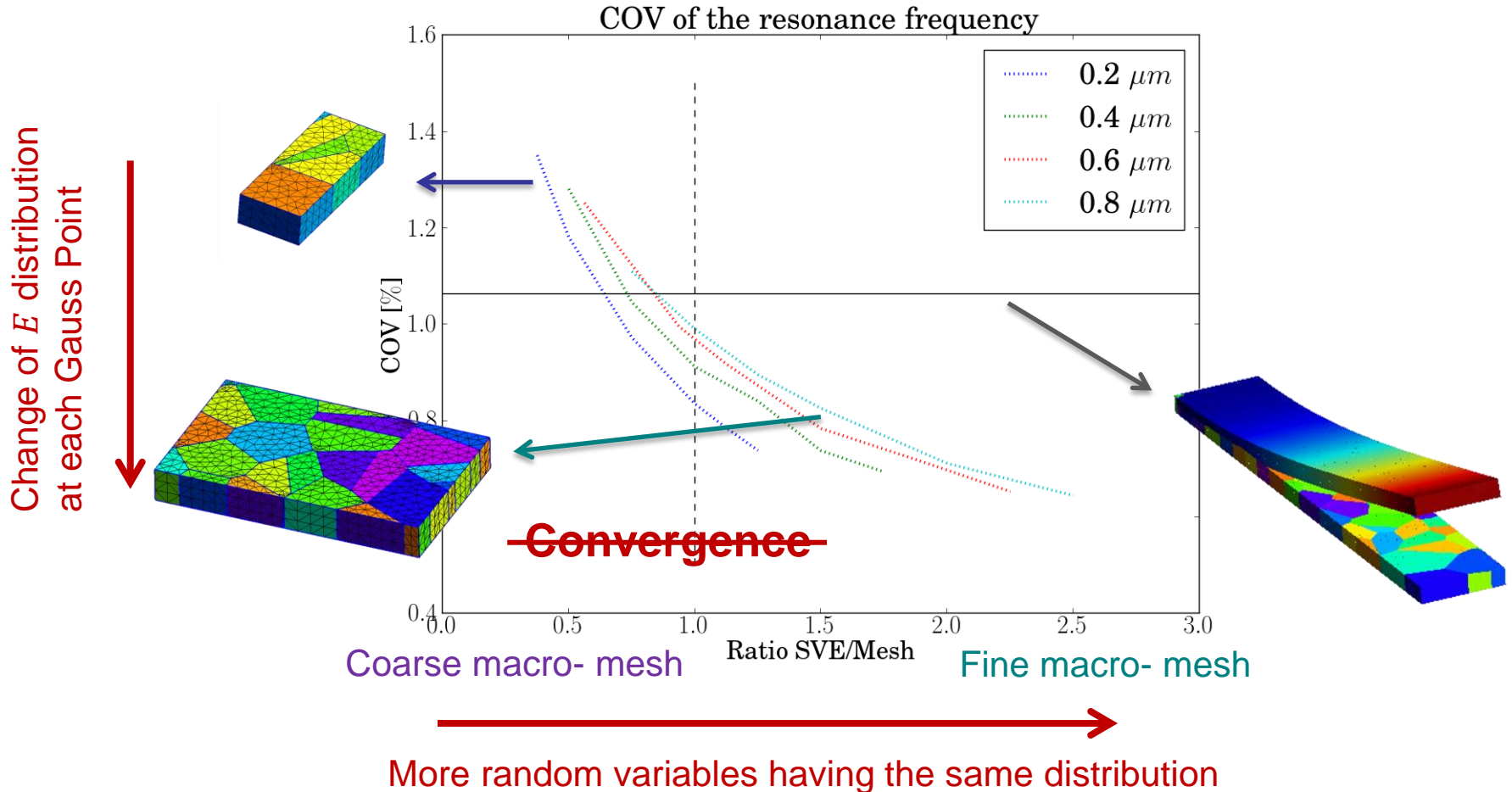
- Use of the meso-scale distribution with macro-scale finite elements
  - Beam macro-scale finite elements
  - Use of the meso-scale distribution as a random variable
  - Monte-Carlo simulations



- No convergence: the macro-scale distribution (first resonance frequency) depends on SVE and mesh sizes

# From the micro-scale to the meso-scale

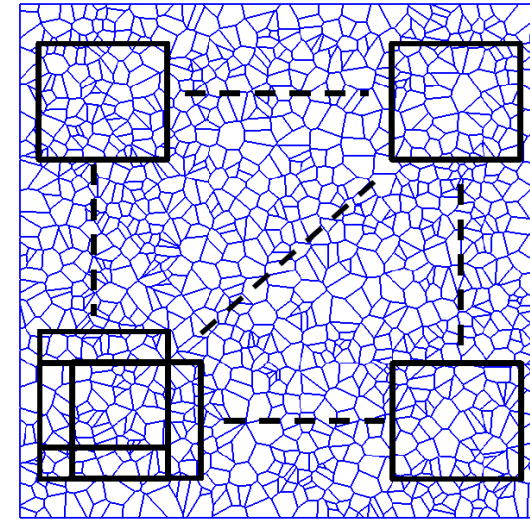
- Use of the meso-scale distribution with macro-scale finite elements
  - Beam macro-scale finite elements
  - Use of the meso-scale distribution as a random variable
  - Monte-Carlo simulations



# From the micro-scale to the meso-scale

- Introduction of the (meso-scale) spatial correlation
  - SVEs extracted at different distances
  - Spatial correlation of the  $r^{\text{th}}$  and  $s^{\text{th}}$  components of the apparent (homogeneous) elasticity tensor  $\mathbb{C}_M$

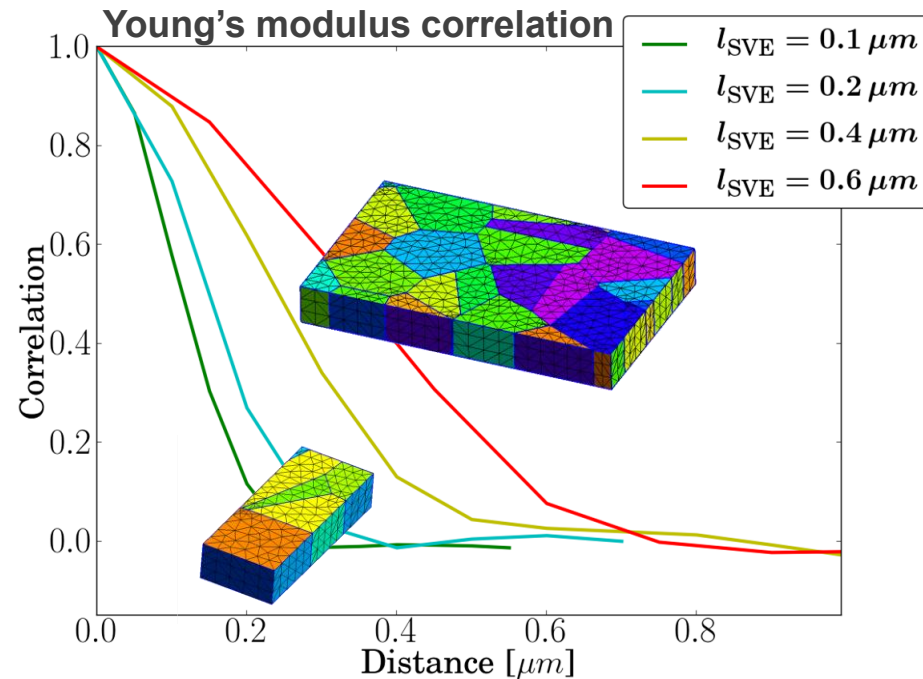
$$R_{\mathbb{C}}^{(rs)}(\boldsymbol{\tau}) = \frac{\mathbb{E}[(\mathbb{C}^{(r)}(\mathbf{x}) - \mathbb{E}(\mathbb{C}^{(r)}))(\mathbb{C}^{(s)}(\mathbf{x} + \boldsymbol{\tau}) - \mathbb{E}(\mathbb{C}^{(s)}))]}{\sqrt{\mathbb{E}[(\mathbb{C}^{(r)} - \mathbb{E}(\mathbb{C}^{(r)}))^2] \mathbb{E}[(\mathbb{C}^{(s)} - \mathbb{E}(\mathbb{C}^{(s)}))^2]}}$$



- Represented by the correlation length:

$$L_{\mathbb{C}}^{(rs)} = \frac{\int_{-\infty}^{\infty} R_{\mathbb{C}}^{(rs)}(r) dr}{R_{\mathbb{C}}^{(rs)}(0)}$$

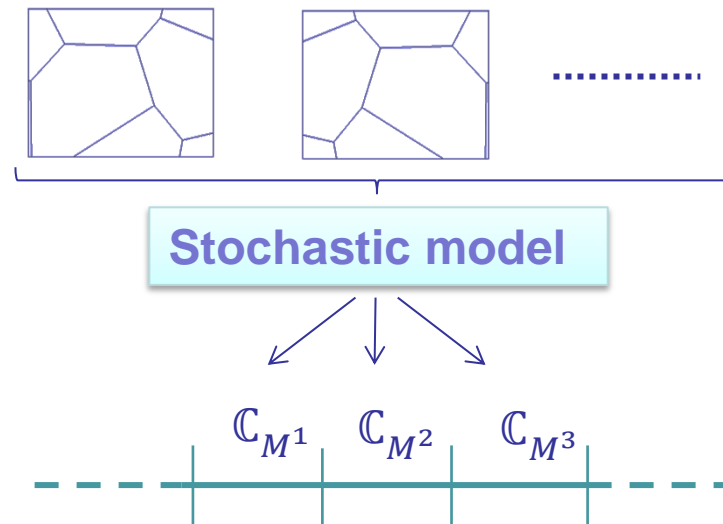
- The correlation length increases with the SVE size



# The meso-scale random field

- Use of the meso-scale distribution with stochastic (macro-scale) finite elements
  - Use of the meso-scale correlated distribution as a random field
  - Meso-scale random field from a generator
  - Monte-Carlo simulations at the macro-scale

## Stochastic model of meso-scale elasticity tensors



# The meso-scale random field

- Generation of the elasticity tensor  $\mathbb{C}_M(x, \theta)$  (matrix  $\mathbf{C}_M$ ) spatially correlated field\*
  - Define a lower isotropic lower bound  $\mathbf{C}_L$  from the silicon crystal tensor  $\mathbf{C}_S$

$$\min_{E, \nu} \|\mathbf{C}_L(E, \nu) - \mathbf{C}_S\| \quad \text{with } \mathbf{C}_L(E, \nu) \leq \mathbf{C}_S$$

- Define the positive semi-definite tensor  $\Delta\mathbf{C}(x, \theta)$  such that

$$\mathbf{C}_M(x, \theta) = \mathbf{C}_L + \Delta\mathbf{C}(x, \theta)$$

- This will ensure the existence of the expectation of  $\mathbf{C}_M^{-1}$
- We now need to generate the spatially correlated random field  $\Delta\mathbf{C}(x, \theta)$

- Cholesky decomposition

$$\Delta\mathbf{C}(x, \theta) = \mathbf{A}(x, \theta)\mathbf{A}(x, \theta)^T \quad \text{with } \mathbf{A}(x, \theta) = \bar{\mathbf{A}} + \mathbf{A}'(x, \theta)$$

Homogeneous  
random field

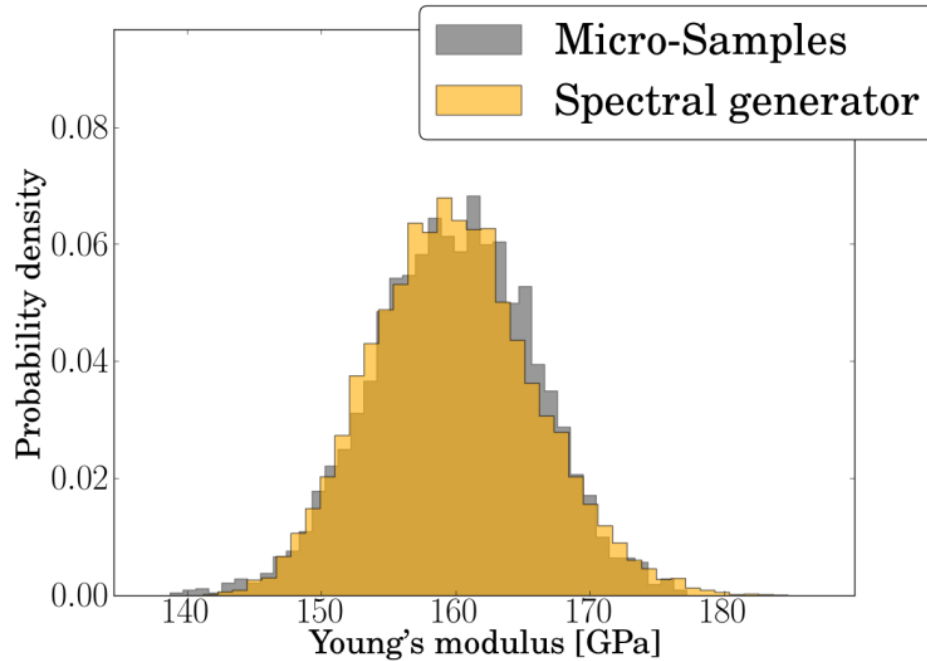
- $\mathbf{A}'(x, \theta)$  is generated using the spatial correlation matrix  $R_{A'}(\tau)$ 
  - Here we use the spectral method\*
  - Assumed Gaussian (can be changed)

\* Lucas, Golinval, Paquay, Nguyen, Noels, Wu, 2016

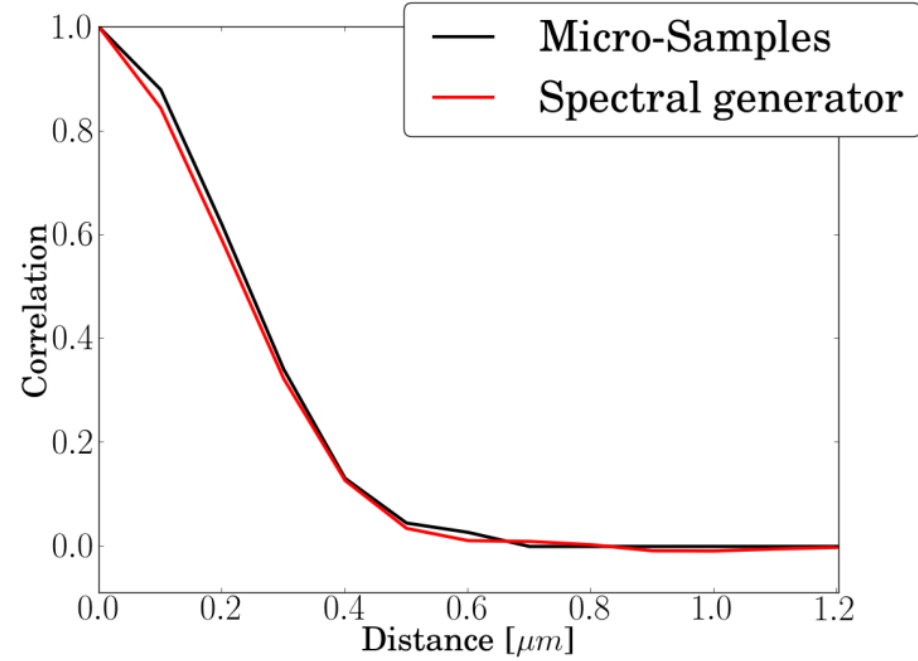
# The meso-scale random field

- Good agreement between:
  - The **samples** of elasticity tensors computed from the homogenization
  - The **generated** elasticity tensors

## Young's modulus distribution



## Young's modulus spatial correlation



	Relative error [%]
mean of $E$	0,026
variance of $E$	0,97

	Micro-samples	Generator
Skewness of $E$	-0,11	0,26
Kurtosis of $E$	2,93	3,02

# From the meso-scale to the macro-scale

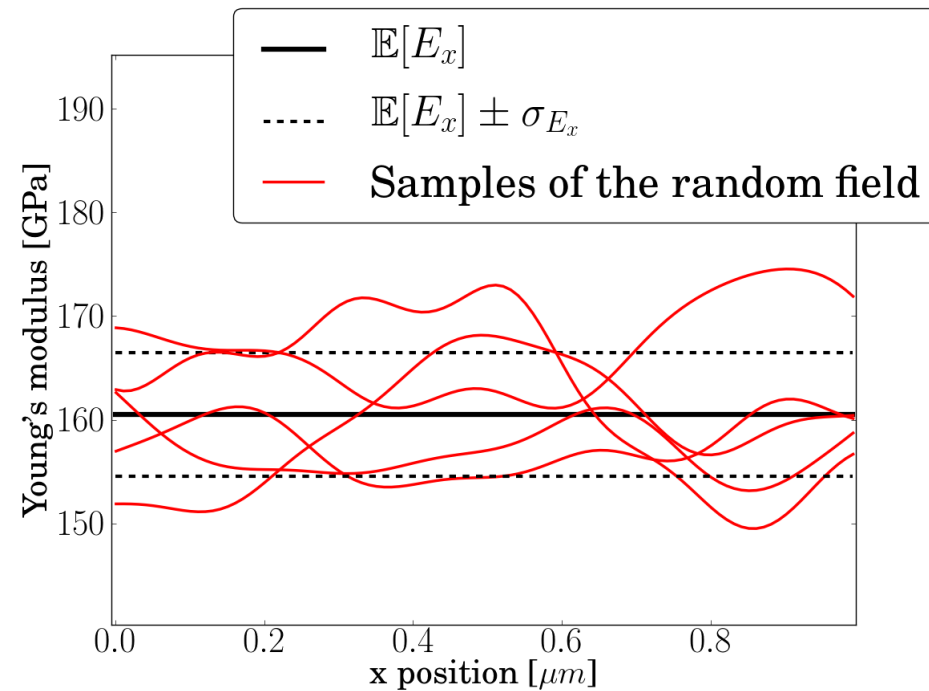
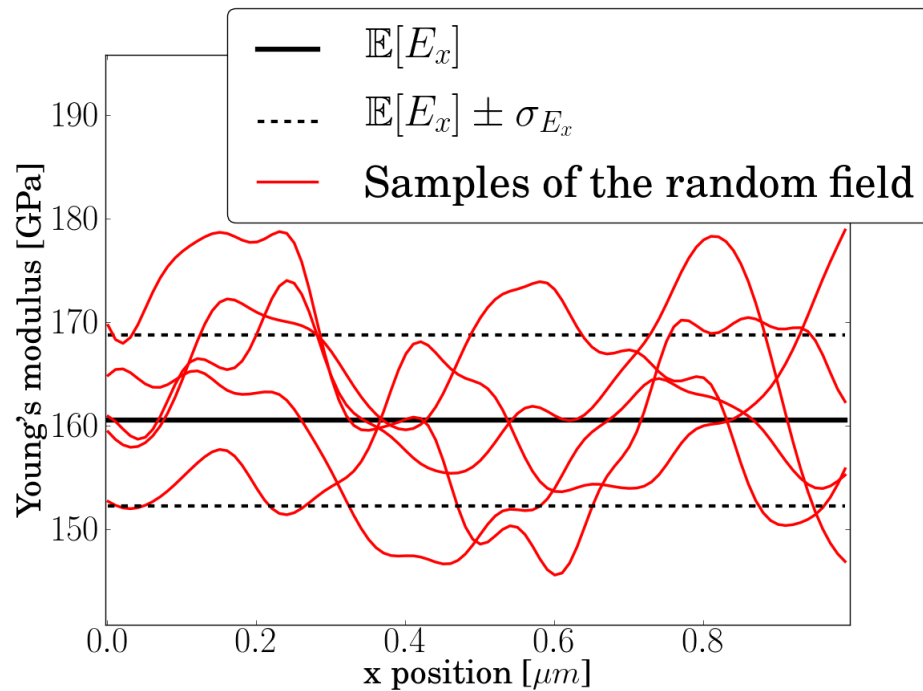
- Stochastic finite element method (SFEM)

- Macro-scale beam elements of size  $l_{\text{mesh}}$
- Use the meso-scale random field obtained using SVEs of size  $l_{\text{SVE}}$
- The meso-scale random field is characterized by the correlation length  $L_{\mathbb{C}}$

Random field with different SVEs sizes

$$L_{\text{SVE}} = 0.1 \mu\text{m}$$

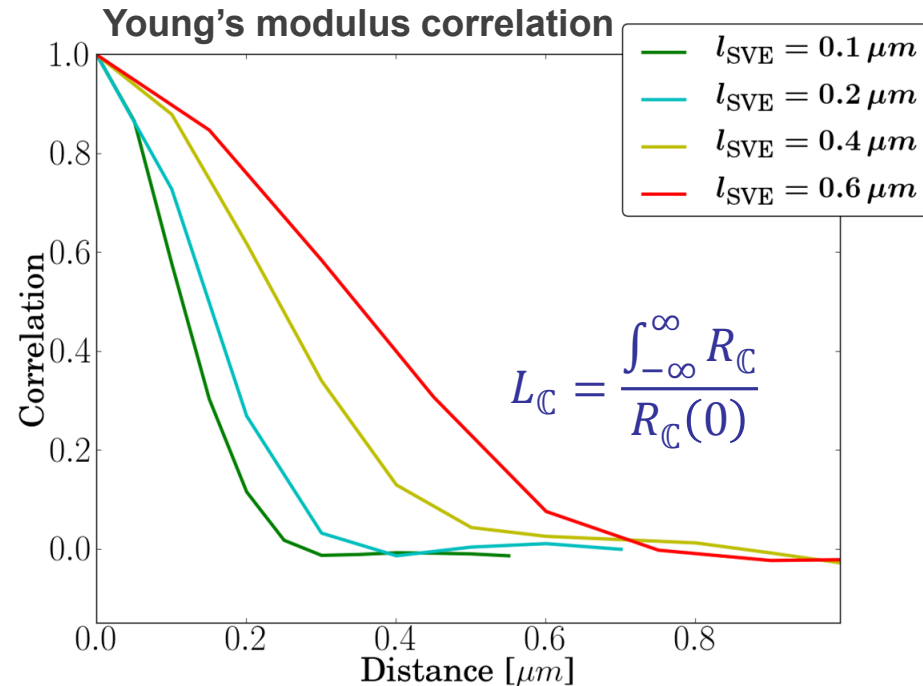
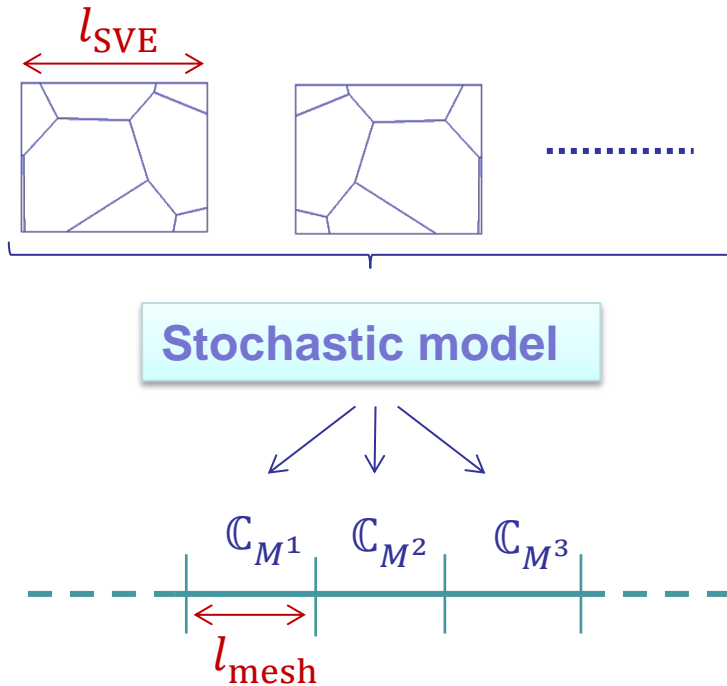
$$L_{\text{SVE}} = 0.4 \mu\text{m}$$





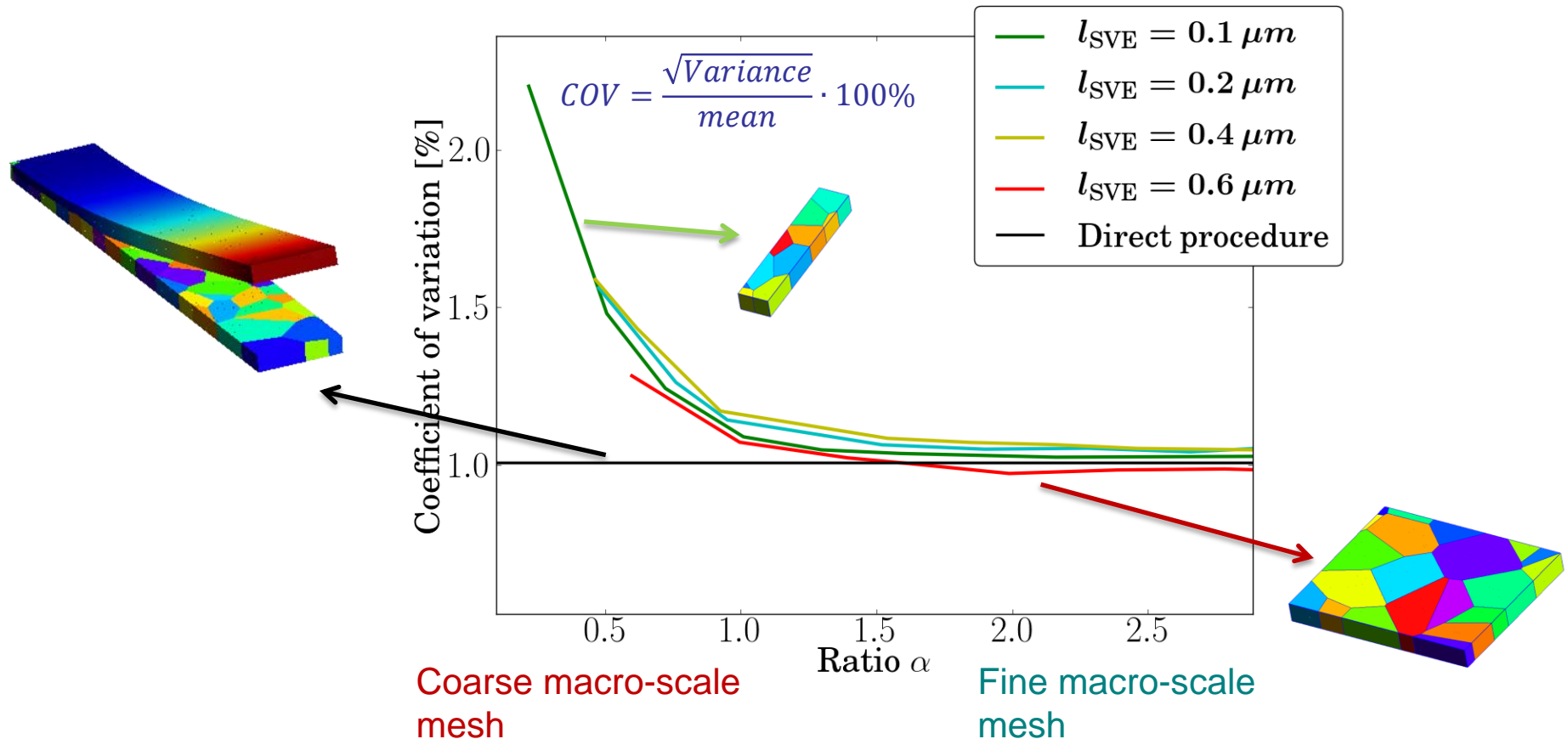
# From the meso-scale to the macro-scale

- The ratio  $\alpha = \frac{L_C}{l_{\text{mesh}}}$ 
  - Links the (macro-scale) finite element size to the correlation length
  - Is related to the SVE size through the correlation length



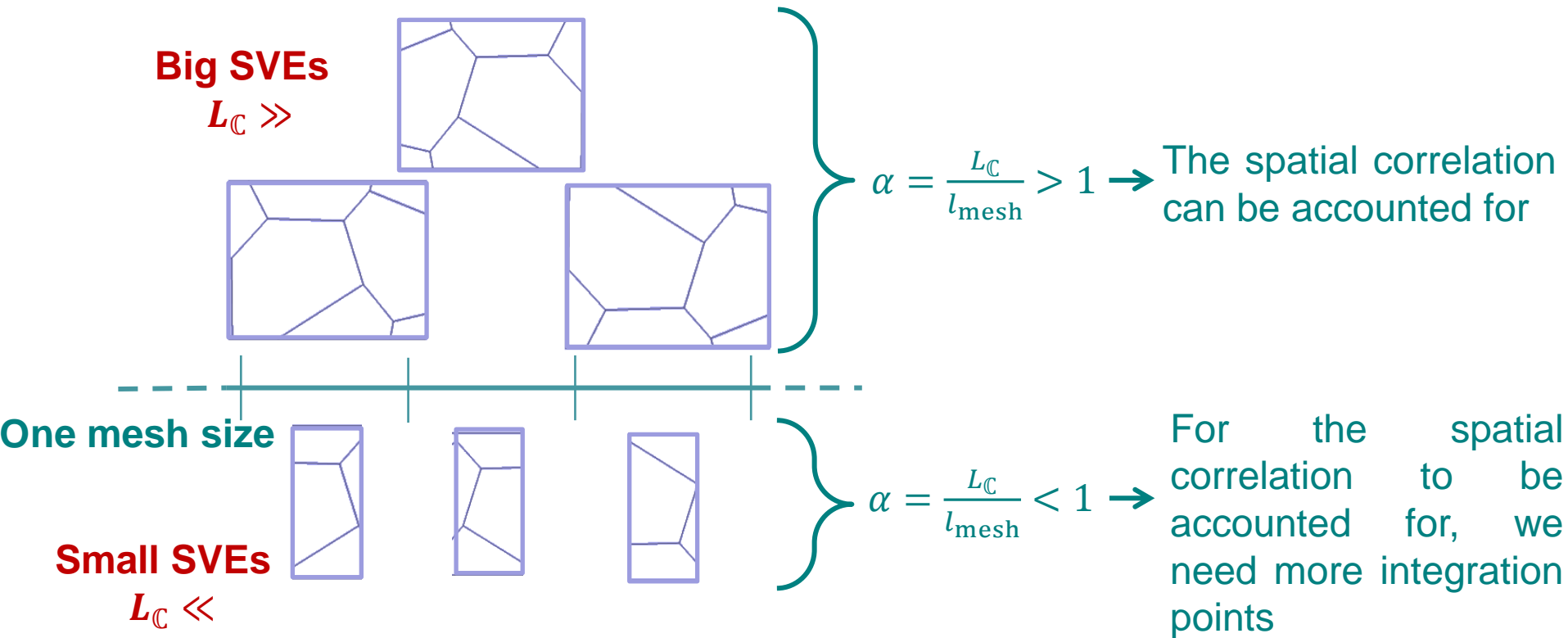
# From the meso-scale to the macro-scale

- Convergence of the 3-scale process
  - In terms of  $\alpha = \frac{l_c}{l_{\text{mesh}}}$
  - First flexion mode of a  $3.2 \mu\text{m}$ -long beam



# From the meso-scale to the macro-scale

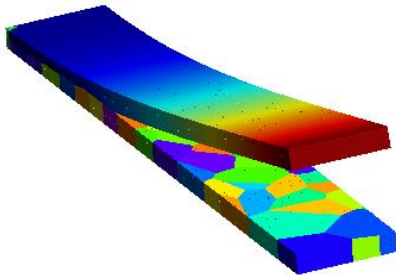
- Effect of the ratio  $\alpha = \frac{l_C}{l_{\text{mesh}}}$



- For extreme values of  $\alpha$ :
  - $\alpha \gg 1$ : no more scale separation if  $L_{\text{SVE}} \sim L_{\text{macro}}$
  - $\alpha \ll 1$ : loss of microstructural details if  $L_{\text{SVE}} \sim L_{\text{micro}}$

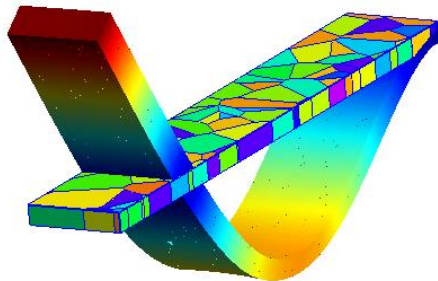
# From the meso-scale to the macro-scale

- Verification of the 3-scale process ( $\alpha \sim 2$ ) with direct Monte-Carlo simulations
  - First bending mode of a  $3.2 \mu\text{m}$ -long beam

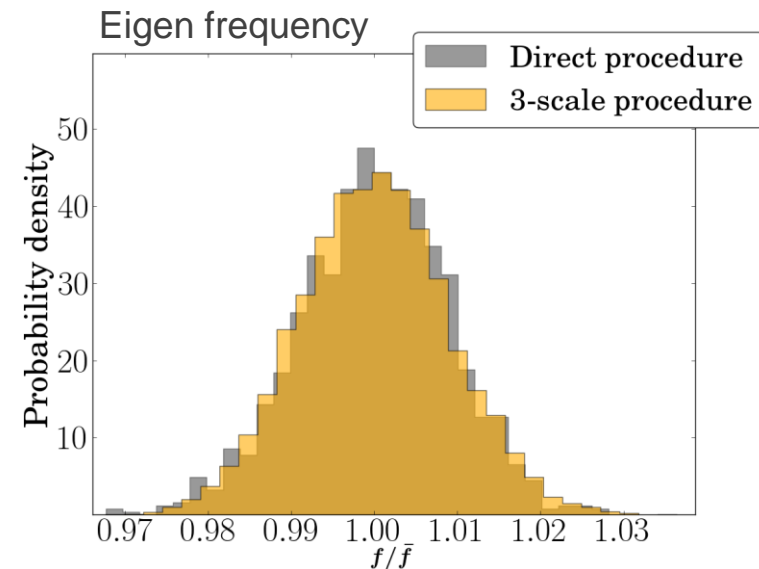
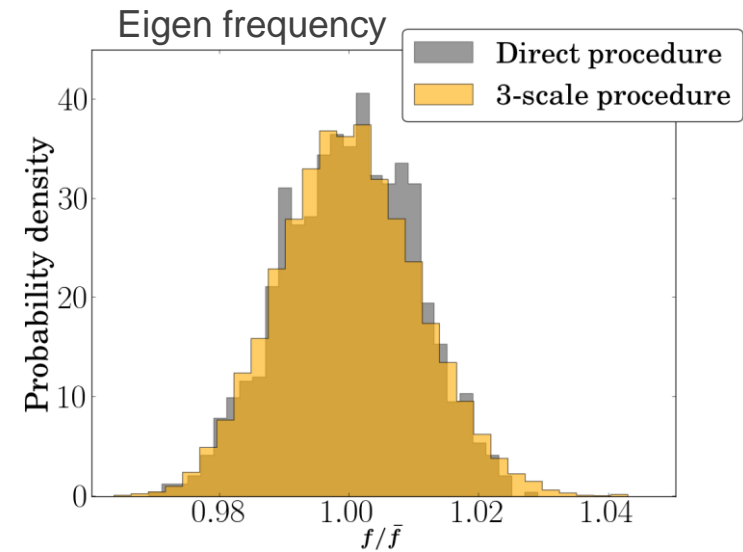


Relative difference  
in the mean: 0.57 %

- Second bending mode of a  $3.2 \mu\text{m}$ -long beam



Relative difference  
in the mean: 0.44 %



- Validate the 1D model on a bigger beam with experimental results
  - **Measures** for appropriate data as inputs: grain sizes, preferred direction, ...
  - **Samples** of 1<sup>st</sup> mode frequency
  - Is the grain orientation the main contribution to the scatter of the first mode?
- Extend the model to 3D
  - Extension to 3D macroscale SFEM (generator already 3D)
  - Extension to thermoelasticity
  - Will permit to study the influence of the **clamp** and **thermoelastic damping**
- Study geometric uncertainties

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Thank you for your attention !